

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/536,910	HAN, IL	
Examiner	Art Unit	
Winnie Yip	3636	

	SEAR	CHED	
			Γ
Class	Subclass	Date	Examiner
135	65 68 72 73	5/30/2006	wsy
		1	
D3	7-8	V	W
		•	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Text Searched in EAST system	5/30/2006	WSY		